

THERMOCOUPLE INSTRUMENTED WAFERS

Thermocouple instrumented wafers are used in semiconductor production processes to test and setup temperature parameters.

The use of an instrumented wafer is optimal to verify temperatures in real working conditions, since there are practically no differences between the probe and the normal parts manufactured.

Our instrumented wafers can cover almost all the needs of testing, and are available with different types of thermocouple, shielding, geometry and connectors.



Specifications

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Substrate	Silicon - other materials on request
Wafer size	100, 125, 150, 200 and 300mm
Clean room compatibility	Class 1 clean room compatible
Geometry	According to customer requests
Substrate supply	From factory or customer (300 mm only from customer)
Probe mounting	Annealed in a tapered hole with HT cement
Thermocouple type	Standard K - other types on request
Shielding	PFA, Kapton, stainless steel clad or ceramic braid
Connections	EIA type 37 connector or small TC plug - other types on request
Packaging	Shock proof shipping package - clean room packaged
Temperature ranges	PFA shielding: up to 250 °C Kapton shielding: up to 300 °C Stainless steel clad: up to 1000 °C Ceramic braid (R type TC) up to 1250 °C (no clean room)

(Specifications are subject to change without any obligation on the part of manufacturer)